


<b>Search Notes</b> 	<b>Application/Control No.</b> 10643672	<b>Applicant(s)/Patent Under Reexamination</b> RAY ET AL.
	<b>Examiner</b> Chawan, Sheela C	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103,118,199,190,305	12/22/06	SCC
709	204,205	12/22/06	SCC
355	75	12/22/06	SCC
715	759,753	12/22/06	SCC
370	260	12/22/06	SCC
379	202.01	12/22/06	SCC
34	117	12/22/06	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	12/22/06	SCC
INVENTOR NAME SEARCH.	12/22/06	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner